Probing deep-ultraviolet optoelectronic processes in hexagonal boron nitride

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Hexagonal boron nitride (hBN) is a van der Waals (vdW) semiconductor with a wide bandgap of ~ 5.96 eV. Despite the indirect bandgap characteristics of hBN, charge carriers excited by high energy electrons or photons efficiently emit luminescence at deep-ultraviolet (DUV) frequencies via strong electron-phonon interaction. In this work, we probe optoelectronic processes at a band edge in hBN by means of optical imaging and spectroscopy at deep ultraviolet frequencies. Our laser excitation spectroscopy shows that strong radiative recombination and carrier excitation processes originate from the pristine structure and the stacking faults in hBN. We further demonstrate prominent electroluminescence and photocurrent generation from hBN by fabricating vdW heterostructures with graphene electrodes. Our work provides a pathway toward efficient DUV light emitting and detection devices based on hBN.

References

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